Search Notes



Application/Control	No.
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10/815,159 Examiner

Dennis Cordray

Applicant(s)/Patent under Reexamination

STEPHENS ET AL.
Art Unit

1731

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Inventor search - PALM	7/12/2005	DRC	
8/107,108.1,109,110,111,115.51;115. 62,115.69,116.1,116.4,120,129,185,4 93,918,919 (cursory)	7/26/2005	DRC	
162/1,6,7,9,13,24,25,26,70,72,73,78,9 0,100,120,146,150,157.2,157.6,158,1 62,168.1,173,179,182,183,184,185,23 1 (cursory)	7/26/2005	DRC	
252/186.1,186.42,186.43;264/122,510 ,518;427/430.1428/311.71,317.1,317. 7,317.9,364,373,375,378,392,532;524 /13,35,321(cursory)	7/26/2005	DRC	
text and text limited class search-see search notes	7/26/2005	DRC	
Specific patent/publication search - EAST (from previous related case)	7/27/2005	DRC	
text and text limited class search-see search notes	7/27/2005	DRC	
Dione Mayes (consultation-double patenting)	8/2/2005	DRC	

Search Notes (continued)



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10/815,159	STEPHENS ET AL.	
Examiner	Art Unit	

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INTERFERENCE SEARCHED			
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Specific patent search	8/2/2005	DRC
Specific patent search	8/3/2005	DRC
update text search	7/12/2006	DRC
update text search	2/2/2007	DRC
update search- EAST (US- PGPUB;USPAT;USOCR;EPO;JPO;D ERWENT)-see search history printout	7/3/2007	DRC